## Notice of References Cited

Application/Control No. 10/707,524	Reexaminati	Applicant(s)/Patent Under Reexamination SHAH ET AL.		
Examiner	Art Unit			
John A. Jefferv	3742	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,170,042	12-1992	Bunn, Albert K.	219/497
	В	US-2,647,198	07-1953	LAUTNER MAX E	392/360
	С	US-5,911,895	06-1999	Porfido et al.	219/221
	D	US-5,014,210	05-1991	Postlewait et al.	700/207
	E	US-6,441,352	08-2002	Groft et al.	219/535
	F	US-2005/0121495	06-2005	Yokoyama, Tetuo	228/009
	G	US-6,803,544	10-2004	Zikes et al.	219/263
	. Н	US-6,740,085	05-2004	Hareyama et al.	606/51
	I	US-2004/0082971	04-2004	Miura, Keisuke	607/003
	J	US-6,873,792	03-2005	Lo, Teh-Liang	392/385
	К	US-6,624,397	09-2003	Tateishi, Art K.	219/508
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	11-52769	02-1999	JP		·
	0	93/19563	09-1993	wo		·
	Р	2002-324652	11-2002	JP		
	Q					
	R				·	
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	•
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.